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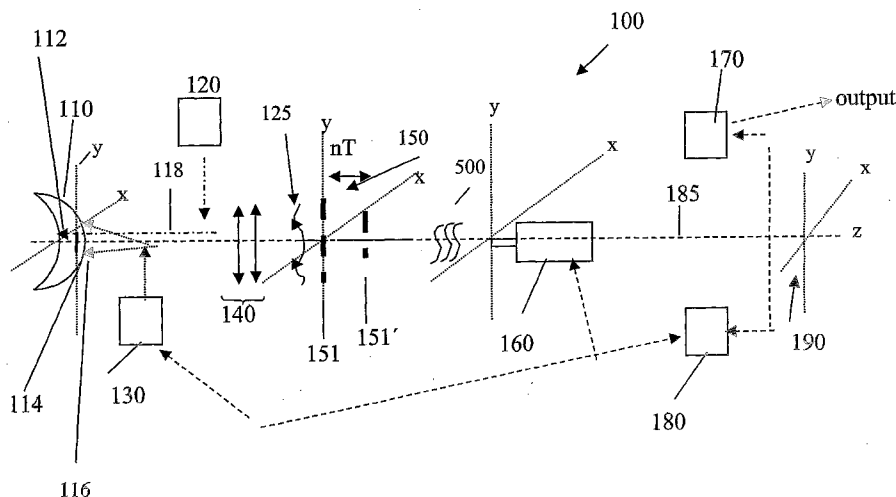
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(54) Title: **MOIRÉ ABERROMETER**



(57) Abstract: An improved moiré deflectometer device (100) for measuring a wavefront aberration of an optical system (110) includes a light source (120) for illuminating a surface area (112) of the optical system, an optical relay system (140) for directing scattered light to a deflectometer component (150) that converts the wavefront into a moiré fringe pattern, a sensor/camera assembly (160) for imaging and displaying the exit pupil (114) of the optical system and the moiré fringe pattern, and a fringe pattern to calculate the wavefront aberration of the optical system, being improved by an illumination source (130) for illuminating the exit pupil (114) of the optical system; and an alignment system (180) cooperating with the illumination source in such a manner to consistently and accurately align a measurement axis of the device to the optical system. An associated method is also disclosed.

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